


<b>Search Notes</b>  	<b>Application/Control No.</b>  10534590	<b>Applicant(s)/Patent Under Reexamination</b>  CHO ET AL.
	<b>Examiner</b>  XIAOZHEN XIE	<b>Art Unit</b>  1646

SEARCHED			
Class	Subclass	Date	Examiner
none			

SEARCH NOTES		
Search Notes	Date	Examiner
EAST: USPAT, US-PGPUB, EPO, JPO, DERWENT (see search history)	10/7/2008	XZ
STN: Medline, Embase, Biosis, CAplus, PCTfull (see search history)	10/7/2008	XZ
Inventor names: searched in PALM	10/7/2008	XZ

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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